


<b>Search Notes</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/726,666	YOSHIOKA ET AL.	
	Examiner	Art Unit	
	Tae H. Yoon	1714	

SEARCHED			
Class	Subclass	Date	Examiner
427	96.1	8-27-06	ay
	98.8		
438	206		
	281		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	8/27/06	ay
Inventor Search	8-27-06	ay
EAST	12-7-06	y